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CONTENTS

FOREWORD 3
1 Scope 5
2 Normative references 5
3 Terms and definitions 5
4 Essential ratings and characteristics 7
4.1 Recommended operating condition 7
4.2 Characteristics 7
5 Test items and methods 7
5.1 Switch type 7
5.2 Static threshold 7
5.2.1 Test method 1 7
5.2.2 Test method 2 8
5.3 Dynamic threshold 10
5.3.1 Test system 10
5.3.2 Test procedure 11

Figure 1 – The schematic drawing of micro-electromechanical inertia shock switch 6
Figure 2 – Test system 1 of static threshold 7
Figure 3 – Test system 2 of static threshold 9
Figure 4 – Circuit diagram of switch 10
Figure 5 – Static threshold of switch 10
Figure 6 – Test system of dynamic threshold 10

Table 1 – Characteristics of the switch threshold 7
Table 2 – Test parameters of static threshold 8
Table 3 – Test parameters of dynamic threshold 11

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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 40: Test methods of micro-electromechanical inertial shock switch threshold

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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 40: Test methods of micro-electromechanical inertial shock switch threshold

1 Scope

This part of IEC 62047 specifies the test conditions and methods of micro-electromechanical inertial shock switch threshold. This document applies to normally open micro-electromechanical inertial shock switch.

2 Normative references

There are no normative references in this document.